

<b>Notice of References Cited</b>		Application/Control No.	Applicant(s)/Patent Under Reexamination SAIKI ET AL.	
		Examiner A. Sefer	Art Unit 2826	Page 1 of 1

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2002/0180678	12-2002	Taira et al.	345/88
*	B	US-6,706,339	03-2004	Miyatake et al.	428/1.31
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	K	US-			
	L	US-			
	M	US-			

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**NON-PATENT DOCUMENTS**

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